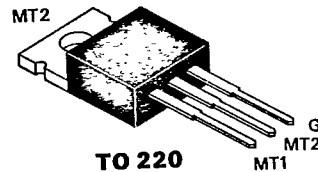


TAG SEMICONDUCTORS LTD

**T1013BH -
T1013NH TRIACS****10.0 A 200-800 V
50/50/50/75 mA**

The T1013 series of TRIAC's are high performance glass passivated PNP devices. These parts are intended for general purpose applications where high gate insensitivity is required.

**Absolute Maximum Ratings** $T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Part Nr.	Symbol	Min.	Max.	Unit	Test Conditions
Repetitive Peak Off State Voltage	T1013BH	V_{DRM}	200		V	[$T_j = -40^\circ\text{C}$ to 125°C $R_{GK} = 1\text{K}\Omega$]
	T1013DH		400		V	
	T1013MH		600		V	
	T1013NH		800		V	
On-State Current		$I_{T(RMS)}$	10		A	All Conduction Angles $T_C = 85^\circ\text{C}$
Nonrept. On-State Current		I_{TSM}	110		A	Half Cycle, 60 Hz
Nonrept. On-State Current		I_{TSM}	100		A	Half Cycle, 50 Hz
Fusing Current		I_{ft}	50		A^2s	$t = 10\text{ ms}$
Peak Gate Current		I_{GM}	4		A	$10\mu\text{s max.}$
Peak Gate Dissipation		P_{GM}	10		W	$10\mu\text{s max.}$
Gate Dissipation		$P_{G(AV)}$	1		W	20 ms max.
Operating Temperature		T_j	-40	125	$^\circ\text{C}$	
Storage Temperature		T_{stg}	-40	125	$^\circ\text{C}$	
Soldering Temperature		T_{sld}		250	$^\circ\text{C}$	1.6 mm from case, 10 s max.

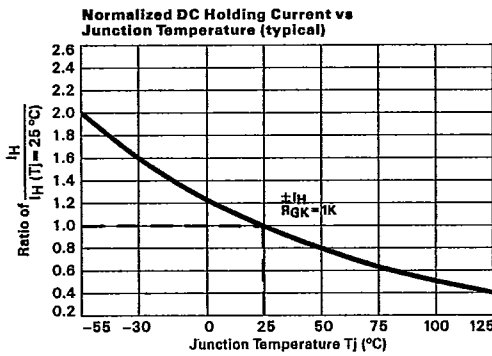
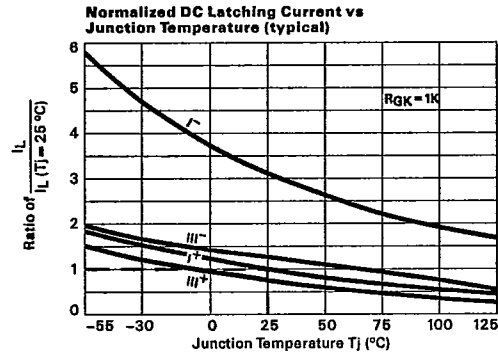
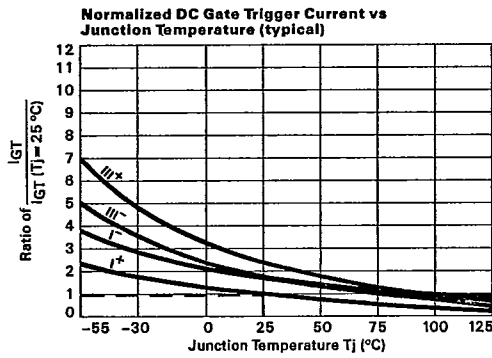
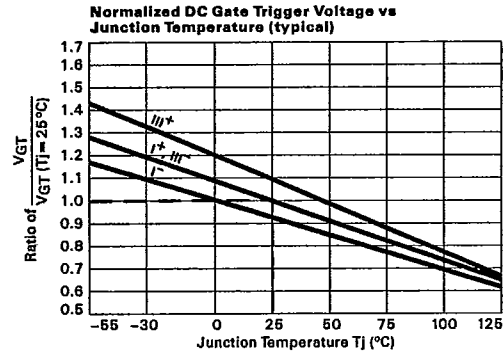
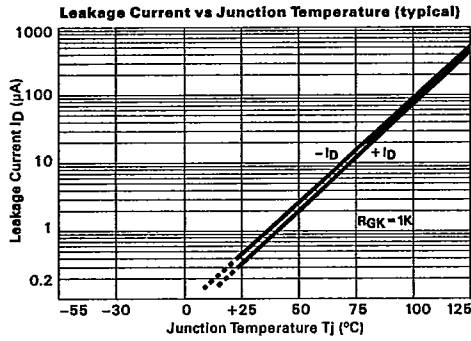
Electrical Characteristics $T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Min.	Max.	Unit	Test Conditions
Off-State Leakage Current	I_{DRM}		2	mA	$V_D = V_{DRM}$ $R_{GK} = 1\text{K}\Omega$ $T_j = 125^\circ\text{C}$
Off-State Leakage Current	I_{DRM}		10	μA	$V_D = V_{DRM}$ $R_{GK} = 1\text{K}\Omega$ $T_j = 25^\circ\text{C}$
On-State Voltage	V_T		1.75	V	at $I_T = 15\text{ A}$, $T_j = 25^\circ\text{C}$
On-State Threshold Voltage	$V_{T(TO)}$		1.05	V	$T_j = 125^\circ\text{C}$
On-State Slope Resistance	r_T		52	$\text{m}\Omega$	$T_j = 125^\circ\text{C}$
Gate Trigger Current	$I_{GT I+}$ (1)		50	mA	$V_D = 12\text{ V}$
	$I_{GT I-}$ (2)		50	mA	$V_D = 12\text{ V}$
	$I_{GT III-}$ (3)		50	mA	$V_D = 12\text{ V}$
	$I_{GT III+}$ (4)		75	mA	$V_D = 12\text{ V}$
Gate Trigger Voltage	V_{GT}		2.5	V	$V_D = 12\text{ V}$ All Quadrants
Holding Current	I_H		75	mA	$R_{GK} = 1\text{K}\Omega$
Critical Rate of Voltage Rise	dv/dt	500		$\text{V}/\mu\text{s}$	$V_D = .67 \times V_{DRM}$ $R_{GK} = 1\text{K}\Omega$ $T_j = 125^\circ\text{C}$
Critical Rate of Rise, Off-State	dv/dt_c	5		$\text{V}/\mu\text{s}$	$I_T = 10\text{ A}$ $di/dt = 4.45\text{ A/ms}$ $T_C = 85^\circ\text{C}$
Thermal Resistance junc. to case	$R_{\theta jc}$		2.5	K/W	
Thermal Resistance junc. to amb.	$R_{\theta ja}$		60	K/W	

T10

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**Typical Characteristics
T10 - Chips**



T10

**Typical Characteristics
T10 - Packaged Parts**

